



(19) **United States**

(12) **Patent Application Publication**

Allen et al.

(10) Pub. No.: US 2024/0214528 A1

(43) **Pub. Date:** **Jun. 27, 2024**

(54) **OBJECT INSPECTION SYSTEM AND METHOD FOR INSPECTING AN OBJECT**

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(21) Appl. No.: 18/431,075

(22) Filed: **Feb. 2, 2024**

### Related U.S. Application Data

(63) Continuation of application No. 17/696,268, filed on Mar. 16, 2022, now Pat. No. 11,937,020, which is a continuation of application No. 16/866,110, filed on May 4, 2020, now Pat. No. 11,310,467, which is a continuation of application No. 15/932,865, filed on May 9, 2018, now abandoned.

(60) Provisional application No. 62/511,404, filed on May 26, 2017, provisional application No. 62/504,534, filed on May 11, 2017, provisional application No. 62/504,538, filed on May 11, 2017.

## Publication Classification

(51) **Int. Cl.**

**H04N 7/18** (2006.01)

**G01N 21/88** (2006.01)

**G01N 21/89** (2006.01)

**G06T 7/00** (2006.01)

**G06T 7/73** (2006.01)

**H04N 17/00** (2006.01)

*H04N 23/56* (2006.01)

*H04N 23/90* (2006.01)

(52) U.S. Cl.

CPC ..... **H04N 7/181** (2013.01); **G01N 21/8851**

(2013.01); **G01N 21/89** (2013.01); **G06T**

*G06T 7/0004* (2013.01); *G06T 7/0008* (2013.01);

**G06T 7/001** (2013.01); **G06T 7/73** (2017.01);

***H04N 7/188 (2013.01); H04N 17/002***

(2013.01); *H04N* 23/56 (2023.01); *H04N*

**23/90** (2023.01); **G06T 2207/10152** (2013.01);

G06T 2207/30156 (2013.01)

(57)

## ABSTRACT

An object inspection system and a method for detecting defects which utilizes a plurality of cameras and lights to capture images of a portion of an object and which uses the captured images to determine the presence of a defect upon a surface, such as surface, of the object and which may communicated the location of the identified defect to an automated defect repair assembly.

